

In the specification:

Page 1, cancel lines 4-9 and substitute therefor:

*CROSS-REFERENCE TO RELATED APPLICATION*

The invention described and claimed hereinbelow is also described in German Patent Application DE 10 2004 026 182.2 filed on May 28, 2004. This German Patent Application, whose subject matter is incorporated here by reference, provides the basis for a claim of priority of invention under 35 U.S.C. 119(a)-(d).

*BACKGROUND OF THE INVENTION*

The present invention relates to a method for reducing interference signal influences on a high-frequency measurement device, and also to a corresponding high-frequency measurement device.

Page 3 after line 8, insert:

*SUMMARY OF THE INVENTION*

Page 3, cancel line 14 in its entirety.

Page 4, cancel lines 21-22 in their entirety.

Page 7, cancel line 23 in its entirety.

Page 8, before line 1 insert:

*BRIEF DESCRIPTION OF THE DRAWINGS*

Page 8, before line 5, please insert:

*DESCRIPTION OF PREFERRED EMBODIMENTS*

Page 11, cancel lines 16-19 and substitute therefor:

Ideally, the process begins with the maximum possible scan rate of the analog/digital converter before this rate is successively decreased, since lower scan rates result in a prolonged measurement duration. The variation of the scan rate of the analog/digital converter can advantageously be executed by a microcontroller 36.